

<b>Notice of References Cited</b>	Application/Control No. 10/781,653	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner John L. Goodrow	Art Unit 1756	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0165761	09-2003	Arai et al.	430/108.6
*	C	US-6,022,661	02-2000	Kurose et al.	430/108.7
*	D	US-2003/0190543	10-2003	Sugiura et al.	430/108.6
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	J	US-			
	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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